Application/Control No. Applicant(s)/Patent Under Reexamination 09/886,064 HAITSMA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Shin-Hon Chen 2131 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 382/100 US-6,633,653 10-2003 Hobson et al. Α US-В US-С US-D US-Ε US-F US-G USн US-US-J US-K US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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